

Search Notes

Application/Control No.

10/781,590

Examiner

Jim Vannucci

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2828

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
lens, reflective, reflector, laser, photo detector	9/30/2005	JV